

Features

- 72-Pin Single-In-Line Memory Module
- Performance:

		-60	-70
t_{RAC}	$\overline{RAS}$ Access Time	60ns	70ns
t_{CAC}	$\overline{CAS}$ Access Time	15ns	20ns
t_{AA}	Access Time From Address	30ns	35ns
t_{RC}	Cycle Time	110ns	130ns
t_{PC}	Fast Page Mode Cycle Time	40ns	45ns

- High Performance CMOS process
- Single 5V, $\pm 0.5V$ Power Supply
- All inputs & outputs are fully TTL & CMOS compatible
- Low active current dissipation
- Fast Page Mode access cycle
- Refresh Modes: $\overline{RAS}$ -Only, CBR, and Hidden Refresh
- 2048 refresh cycles distributed across 32ms
- 11/11 Addressing (Row/Column)
- Optimized for use in byte-write parity applications
- Tin/lead or gold tabs
- DRAMs in SOJ Package

Description

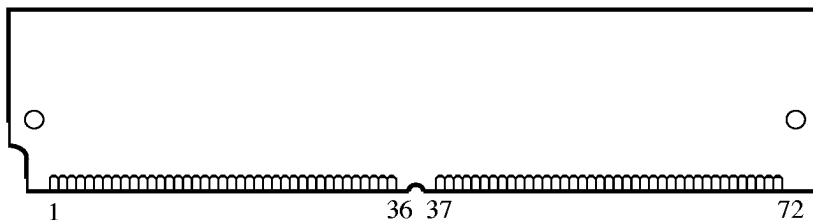
The IBM11D8360E is a 32MB 72-pin 4-byte single in-line memory module (SIMM). The module is organized as an 8Mx36 high speed memory array, and is configured as two 4Mx36 banks - each independently selectable via unique $\overline{RAS}$ inputs. The assembly is intended for use in 36 and 72 bit applications where interleave of 9 or 18 bit words is not required. It is manufactured with sixteen 4Mx4 devices, each in a 300mil package, and two 4Mx4 'Quad CAS' devices for parity. The use of 'Quad CAS' devices results in reduced SIMM height and

lower power dissipation.

The IBM11D4360E is a 16MB half populated version, manufactured with eight 4Mx4 devices and one 4Mx4 'Quad CAS' device.

The IBM 72-Pin SIMMs provide a high performance, flexible 4-byte interface in a 4.25" long footprint. Related products include the 8Mx32 non-parity SIMM, IBM11D8320B, as well as other density offerings.

Card Outline



Pin Description

RAS0, RAS2	Row Address Strobe (4MB)
RAS0 - RAS3	Row Address Strobe (8MB)
CAS0 - CAS3	Column Address Strobe
WE	Read/write Input
A0 - A10	Address Inputs
DQ0-7, 9-16, 18-25, 27-34	Data Input/output
PQ8, 17, 26, 35	Parity Input/output
V _{CC}	Power (+5V)
V _{SS}	Ground
NC	No Connect
PD1 - PD4	Presence Detects

Pinout

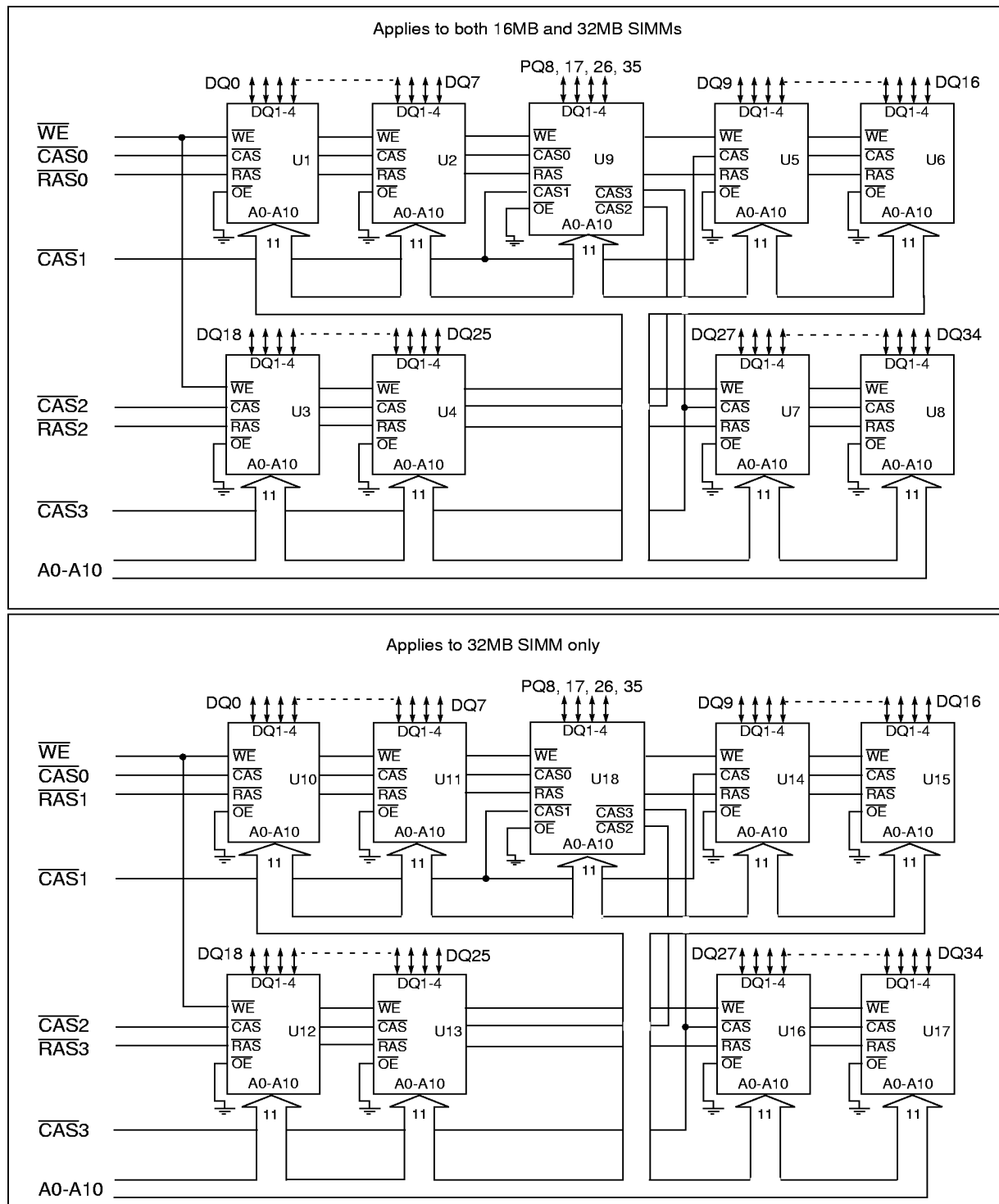
Pin#	Name	Pin#	Name	Pin#	Name
1	V _{SS}	25	DQ24	49	DQ9
2	DQ0	26	DQ7	50	DQ27
3	DQ18	27	DQ25	51	DQ10
4	DQ1	28	A7	52	DQ28
5	DQ19	29	NC	53	DQ11
6	DQ2	30	V _{CC}	54	DQ29
7	DQ20	31	A8	55	DQ12
8	DQ3	32	A9	56	DQ30
9	DQ21	33	RAS3*	57	DQ13
10	V _{CC}	34	RAS2	58	DQ31
11	NC	35	PQ26	59	V _{CC}
12	A0	36	PQ8	60	DQ32
13	A1	37	PQ17	61	DQ14
14	A2	38	PQ35	62	DQ33
15	A3	39	V _{SS}	63	DQ15
16	A4	40	CAS0	64	DQ34
17	A5	41	CAS2	65	DQ16
18	A6	42	CAS3	66	NC
19	A10	43	CAS1	67	PD1
20	DQ4	44	RAS0	68	PD2
21	DQ22	45	RAS1*	69	PD3
22	DQ5	46	NC	70	PD4
23	DQ23	47	WE	71	NC
24	DQ6	48	NC	72	V _{SS}

1. DQ numbering is compatible with non-parity (x32) version.
2. * RAS1 and RAS3 are "NC" on 16MB SIMM.

Ordering Information

Part Number	Organization	Speed	Addr.	Leads	Dimensions	Notes
IBM11D4360E-60J	4M x 36	60ns	11/11	Sn/Pb	4.25" x 1" x .205"	1
IBM11D4360E-70J		70ns		Sn/Pb		
IBM11D8360E-60J	8M x 36	60ns		Sn/Pb	4.25" x 1" x .360"	
IBM11D8360E-70J		70ns		Sn/Pb		
IBM11E4360E-60J	4M x 36	60ns		Au	4.25" x 1" x .205"	
IBM11E4360E-70J		70ns		Au		
IBM11E8360E-60J	8M x 36	60ns		Au	4.25" x 1" x .360"	
IBM11E8360E-70J		70ns		Au		
1. DRAM package designator appended to speed portion of part number on assemblies beginning with die rev E.						

Block Diagrams



Truth Table

Function		$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{WE}}$	Row Address	Column Address	All DQ, PQ bits
Standby		H	H→X	X	X	X	High Impedance
Read		L	L	H	Row	Col	Valid Data Out
Early-Write		L	L	L	Row	Col	Valid Data In
Fast Page Mode - Read: 1st Cycle		L	H→L	H	Row	Col	Valid Data Out
Subsequent Cycles		L	H→L	H	N/A	Col	Valid Data Out
Fast Page Mode - Write: 1st Cycle		L	H→L	L	Row	Col	Valid Data In
Subsequent Cycles		L	H→L	L	N/A	Col	Valid Data In
$\overline{\text{RAS}}$ -Only Refresh		L	H	X	Row	N/A	High Impedance
$\overline{\text{CAS}}$ -Before- $\overline{\text{RAS}}$ Refresh		H→L	L	H	X	X	High Impedance
Hidden Refresh	Read	L→H→L	L	H	Row	Col	Data Out
	Write	L→H→L	L	L	Row	Col	Data In

Presence Detect

Pin	4M x 36		8M x 36	
	-60	-70	-60	-70
PD1	V _{SS}	V _{SS}	NC	NC
PD2	NC	NC	V _{SS}	V _{SS}
PD3	NC	V _{SS}	NC	V _{SS}
PD4	NC	NC	NC	NC

1. NC= OPEN, V_{SS} = GND

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	Notes
V _{CC}	Power Supply Voltage	-1.0 to +6.0	V	1
V _{IN}	Input Voltage	-1.0 to +6.0	V	1
V _{OUT}	Output Voltage	-1.0 to +6.0	V	1
T _{OPR}	Operating Temperature	0 to +70	°C	1
T _{STG}	Storage Temperature	-55 to +125	°C	1
P _D	Power Dissipation	4.3 (4MB) 8.60 (8MB)	W	1, 2
I _{OUT}	Short Circuit Output Current	50	mA	1

1. Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only, and device functional operation at or above the conditions indicated is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

2. Maximum power occurs when all banks are active (refresh cycle).



Recommended DC Operating Conditions ($T_A = 0$ to 70°C)

Symbol	Parameter	Min	Typ	Max	Units	Notes
V_{CC}	Supply Voltage	4.5	5.0	5.5	V	1
V_{IH}	Input High Voltage	2.4	—	$V_{CC} + 0.5$	V	1, 2
V_{IL}	Input Low Voltage	0.0	—	0.8	V	1, 2

1. All voltages referenced to V_{SS} .
2. V_{IH} may overshoot to $V_{CC} + 2.0\text{V}$ for pulse widths of $\leq 4.0\text{ns}$ (or $V_{CC} + 1.0\text{V}$ for $\leq 8.0\text{ns}$). Additionally, V_{IL} may undershoot to -2.0V for pulse widths $\leq 4.0\text{ns}$ (or -1.0V for $\leq 8.0\text{ns}$). Pulse widths measured at 50% points with amplitude measured peak to DC reference.

Capacitance ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5.0\text{V} \pm 0.5\text{V}$)

Symbol	Parameter	4M x 36 Max	8M x 36 Max	Units
C_{I1}	Input Capacitance (A0-A10)	55	105	pF
C_{I2}	Input Capacitance (16MB: $\overline{RAS}0$, 32MB: $\overline{RAS}0$, 1)	47	48	pF
C_{I3}	Input Capacitance (16MB: $\overline{RAS}2$, 32MB: $\overline{RAS}2$, 3)	43	45	pF
C_{I4}	Input Capacitance ($\overline{CAS}$)	30	54	pF
C_{I5}	Input Capacitance ($\overline{WE}$)	70	137	pF
$C_{I/O}$	Output Capacitance (All DQ, PQ)	12	25	pF

DC Electrical Characteristics (T_A = 0 to +70°C, V_{CC} = 5.0V ± 0.5V)

Symbol	Parameter		4M x 36		8M x 36		Units	Notes
			Min	Max	Min	Max		
I _{CC1}	Operating Current	-60	—	780	—	798	mA	1, 2, 3
	Average Power Supply Operating Current ($\overline{\text{RAS}}$, $\overline{\text{CAS}}$, Address Cycling: t _{RC} = t _{RC} min)	-70	—	690	—	708		
I _{CC2}	Standby Current (TTL) Power Supply Standby Current ($\overline{\text{RAS}} = \overline{\text{CAS}} \geq V_{IH}$)		—	18	—	36	mA	
I _{CC3}	$\overline{\text{RAS}}$ Only Refresh Current	-60	—	780	—	798	mA	1, 3, 4
	Average Power Supply Current, $\overline{\text{RAS}}$ Only Mode ($\overline{\text{RAS}}$ Cycling, $\overline{\text{CAS}} \geq V_{IH}$; t _{RC} = t _{RC} min)	-70	—	690	—	708		
I _{CC4}	Fast Page Mode Current	-60	—	600	—	618	mA	1, 2, 3
	Average Power Supply Current, Fast Page Mode ($\overline{\text{RAS}} = V_{IL}$, $\overline{\text{CAS}}$, Address Cycling: t _{PC} = t _{PC} min)	-70	—	510	—	528		
I _{CC5}	Standby Current (CMOS) Power Supply Standby Current ($\overline{\text{RAS}} = \overline{\text{CAS}} = V_{CC} - 0.2V$)		—	9	—	18	mA	
I _{CC6}	$\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Current	-60	—	780	—	798	mA	1, 3, 4
	Average Power Supply Current, $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Mode ($\overline{\text{RAS}}$, $\overline{\text{CAS}}$, Cycling: t _{RC} = t _{RC} min)	-70	—	690	—	708		
I _{I(L)}	Input Leakage Current	$\overline{\text{RAS}}0, 1$	-50	+50	-50	+50	μA	
	Input Leakage Current, any input (0.0 ≤ V _{IN} ≤ (V _{CC} < 6.0V))	$\overline{\text{RAS}}2, 3$	-40	+40	-40	+40		
		$\overline{\text{CAS}}$	-30	+30	-60	+60		
	All Other Pins Not Under Test = 0V	All others	-90	+90	-180	+180		
I _{O(L)}	Output Leakage Current (D _{OUT} is disabled, 0.0 ≤ V _{OUT} ≤ V _{CC})		-10	+10	-20	+20	μA	
V _{OH}	Output High Level Output "H" Level Voltage (I _{OUT} = -5mA @ 2.4V)		2.4	—	2.4	—	V	
V _{OL}	Output Low Level Output "L" Level Voltage (I _{OUT} = +4.2mA @ 0.4V)		—	0.4	—	0.4	V	
1. I _{CC1} , I _{CC3} , I _{CC4} and I _{CC6} depend on cycle rate. 2. I _{CC1} , I _{CC4} depend on output loading. Specified values are obtained with the output open. 3. Address can be changed once or less while $\overline{\text{RAS}} = V_{IL}$. In the case of I _{CC4} , it can be changed once or less when $\overline{\text{CAS}} = V_{IH}$. 4. Refresh current is specified for 1 bank active and 1 bank standby.								

AC Characteristics (T_A = 0 to +70°C, V_{CC} = 5.0V ± 0.5V)

- V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} and V_{IL}.
- An initial pause of 100μs is required after power-up followed by 8 $\overline{\text{RAS}}$ only refresh cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycles instead of 8 $\overline{\text{RAS}}$ only refresh cycles is required.
- AC measurements assume t_T = 5ns.

Read, Write, and Refresh Cycles (Common Parameters)

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t _{RC}	Random Read or Write Cycle Time	110	—	130	—	ns	
t _{RP}	$\overline{\text{RAS}}$ Precharge Time	40	—	50	—	ns	
t _{CP}	$\overline{\text{CAS}}$ Precharge Time	10	—	10	—	ns	1
t _{RAS}	$\overline{\text{RAS}}$ Pulse Width	60	10K	70	10K	ns	
t _{CAS}	$\overline{\text{CAS}}$ Pulse Width	15	10K	20	10K	ns	
t _{ASR}	Row Address Setup Time	0	—	0	—	ns	
t _{RAH}	Row Address Hold Time	10	—	10	—	ns	
t _{ASC}	Column Address Setup Time	0	—	0	—	ns	
t _{CAH}	Column Address Hold Time	10	—	15	—	ns	
t _{RCD}	$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay Time	20	45	20	50	ns	2
t _{RAD}	$\overline{\text{RAS}}$ to Column Address Delay Time	15	30	15	35	ns	3
t _{RSH}	$\overline{\text{RAS}}$ Hold Time	15	—	20	—	ns	
t _{CSH}	$\overline{\text{CAS}}$ Hold Time	60	—	70	—	ns	
t _{CRP}	$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time	5	—	5	—	ns	
t _{DZC}	$\overline{\text{CAS}}$ Delay Time from D _{IN}	0	—	0	—	ns	
t _T	Transition Time (Rise and Fall)	3	50	3	50	ns	
t _{GLCH}	Hold Time $\overline{\text{CAS}}$ Low to $\overline{\text{CAS}}$ High	5	—	5	—	ns	4
t _{AR}	Column Address Hold Time Referenced to $\overline{\text{RAS}}$	50	—	55	—	ns	

- Last rising $\overline{\text{CAS}}$ edge to first falling $\overline{\text{CAS}}$ edge.
- Operation within the t_{RCD} (max) limit ensures that t_{RAC} (max) can be met. t_{RCD} (max) is specified as a reference point only: if t_{RCD} is greater than the specified t_{RCD} (max) limit, then access time is controlled by t_{CAC}.
- Operation within the t_{RAD} (max) limit ensures that t_{RAC} (max) can be met. t_{RAD} (max) is specified as a reference point only: If t_{RAD} is greater than the specified t_{RAD} (max) limit, then access time is controlled by t_{AA}.
- Last falling $\overline{\text{CAS}}$ edge to first rising $\overline{\text{CAS}}$ edge.

Write Cycle

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t_{WCS}	Write Command Set Up Time	0	—	0	—	ns	
t_{WCH}	Write Command Hold Time	15	—	15	—	ns	
t_{WP}	Write Command Pulse Width	15	—	15	—	ns	
t_{RWL}	Write Command to $\overline{RAS}$ Lead Time	15	—	20	—	ns	
t_{CWL}	Write Command to $\overline{CAS}$ Lead Time	15	—	20	—	ns	
t_{WCR}	Write Command Hold Time Referenced to $\overline{RAS}$	45	—	55	—	ns	
t_{DHR}	Data Hold Time Referenced to $\overline{RAS}$	45	—	55	—	ns	
t_{DS}	D_{IN} Setup Time	0	—	0	—	ns	
t_{DH}	D_{IN} Hold Time	10	—	15	—	ns	

Read Cycle

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t_{RAC}	Access Time from $\overline{RAS}$	—	60	—	70	ns	1, 2
t_{CAC}	Access Time from $\overline{CAS}$	—	15	—	20	ns	1, 2
t_{AA}	Access Time from Address	—	30	—	35	ns	1, 2
t_{RCS}	Read Command Setup Time	0	—	0	—	ns	
t_{RCH}	Read Command Hold Time to $\overline{CAS}$	0	—	0	—	ns	3
t_{RRH}	Read Command Hold Time to $\overline{RAS}$	0	—	0	—	ns	3
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	30	—	35	—	ns	
t_{CAL}	Column Address to $\overline{CAS}$ Lead Time	—	—	—	—	ns	4
t_{CLZ}	$\overline{CAS}$ to Output in Low-Z	0	—	0	—	ns	
t_{OH}	Output Data Hold Time	0	—	0	—	ns	
t_{CDD}	$\overline{CAS}$ to D_{IN} Delay Time	15	—	20	—	ns	4
t_{OFF}	Output Buffer Turn-off Delay	—	15	—	20	ns	5

1. Measured with the specified current load and 100pF.
2. Access time is determined by the latter of t_{RAC} , t_{CAC} , t_{CPA} , t_{AA} .
3. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
4. This timing parameter is not applicable to this product, but applies to a related product in this family.
5. t_{OFF} (max) defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.



Fast Page Mode Cycle

Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t_{PC}	Fast Page Mode Cycle Time	40	—	45	—	ns	
t_{RASP}	Fast Page Mode $\overline{RAS}$ Pulse Width	60	100K	70	100K	ns	
t_{CPRH}	$\overline{RAS}$ Hold Time from $\overline{CAS}$ Precharge	35	—	40	—	ns	
t_{CPA}	Access Time from $\overline{CAS}$ Precharge	—	35	—	40	ns	1, 2

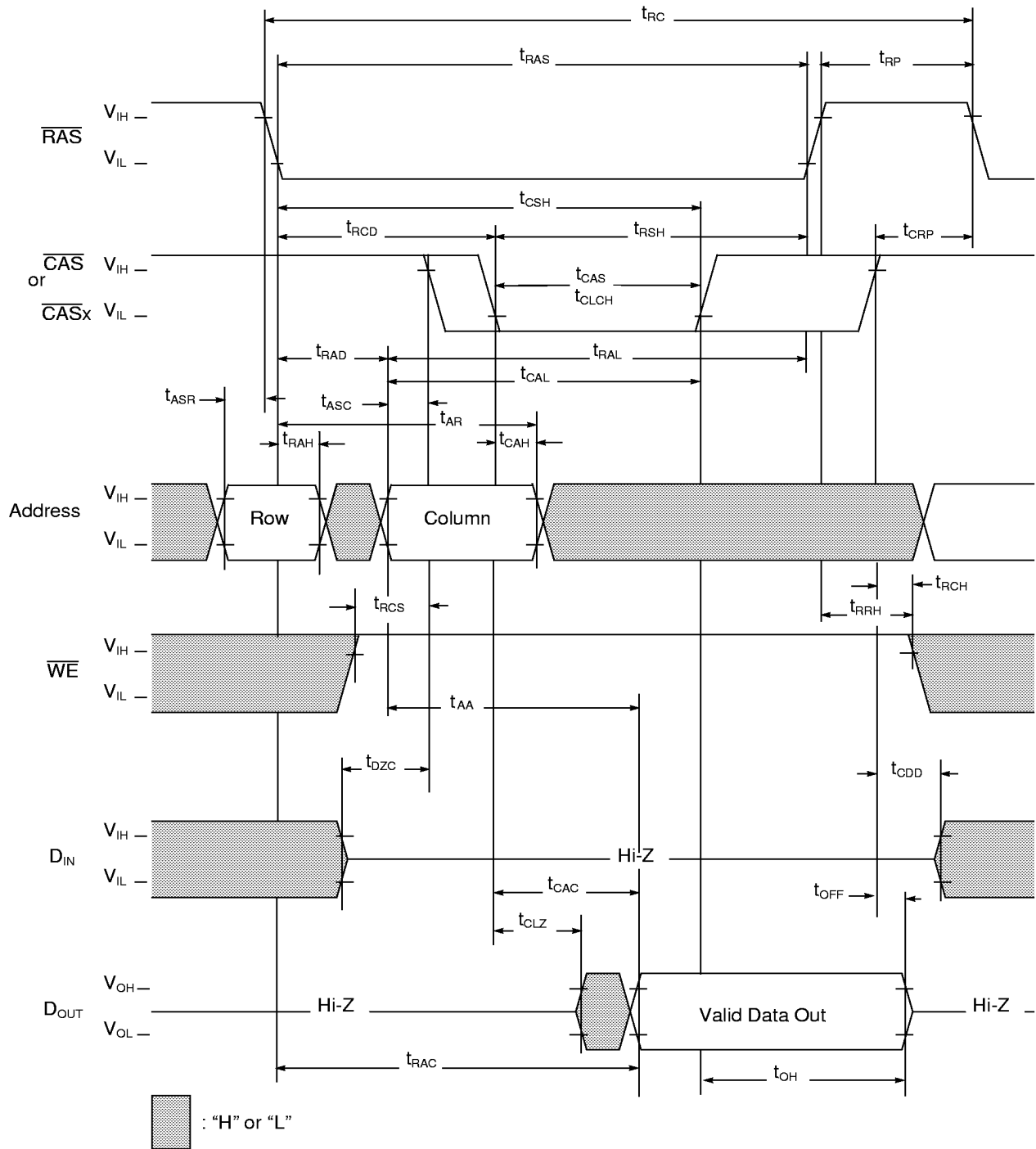
1. Access time is determined by the latter of t_{RAC} , t_{CAC} , t_{CPA} , t_{AA} .
2. Measured with the specified current load and 100pF.

Refresh Cycle

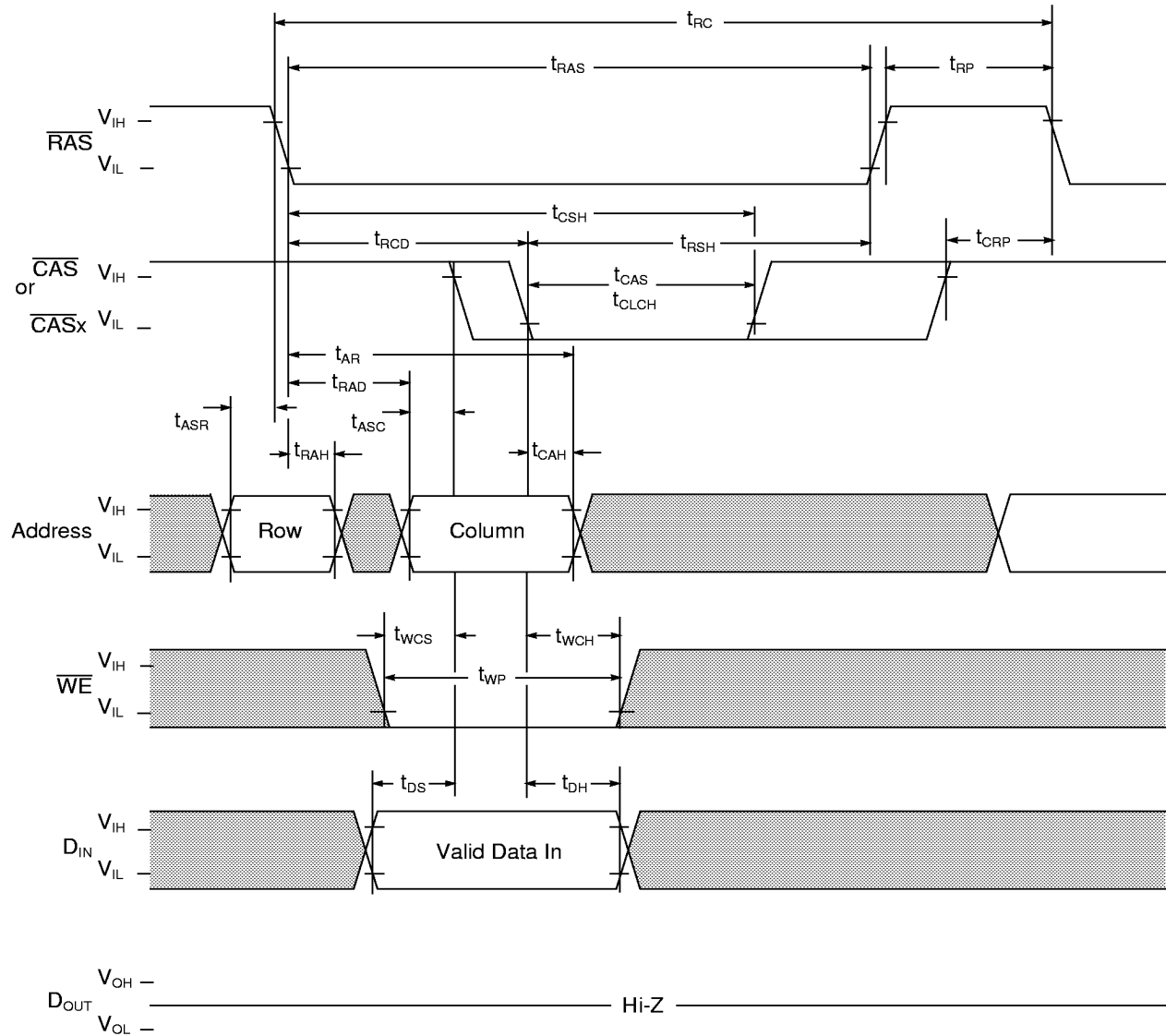
Symbol	Parameter	-60		-70		Units	Notes
		Min	Max	Min	Max		
t_{CHR}	$\overline{CAS}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{CSR}	$\overline{CAS}$ Setup Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{WRP}	$\overline{WE}$ Setup Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{WRH}	$\overline{WE}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{RPC}	$\overline{RAS}$ Precharge to $\overline{CAS}$ Hold Time	0	—	0	—	ns	
t_{REF}	Refresh Period	—	32	—	32	ms	1

1. 2048 refreshes are required every 32ms.

Read

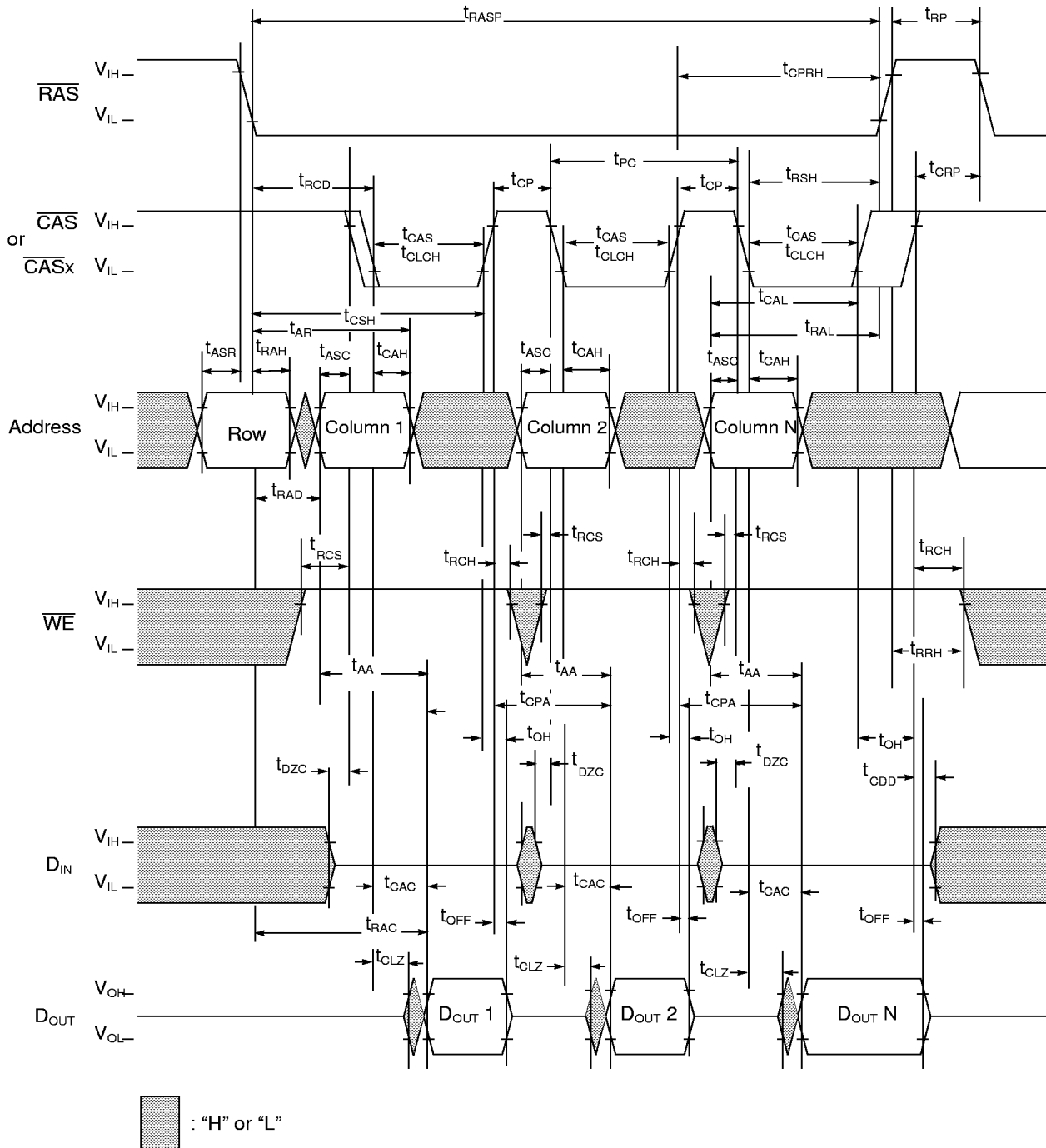


Write Cycle (Early Write)

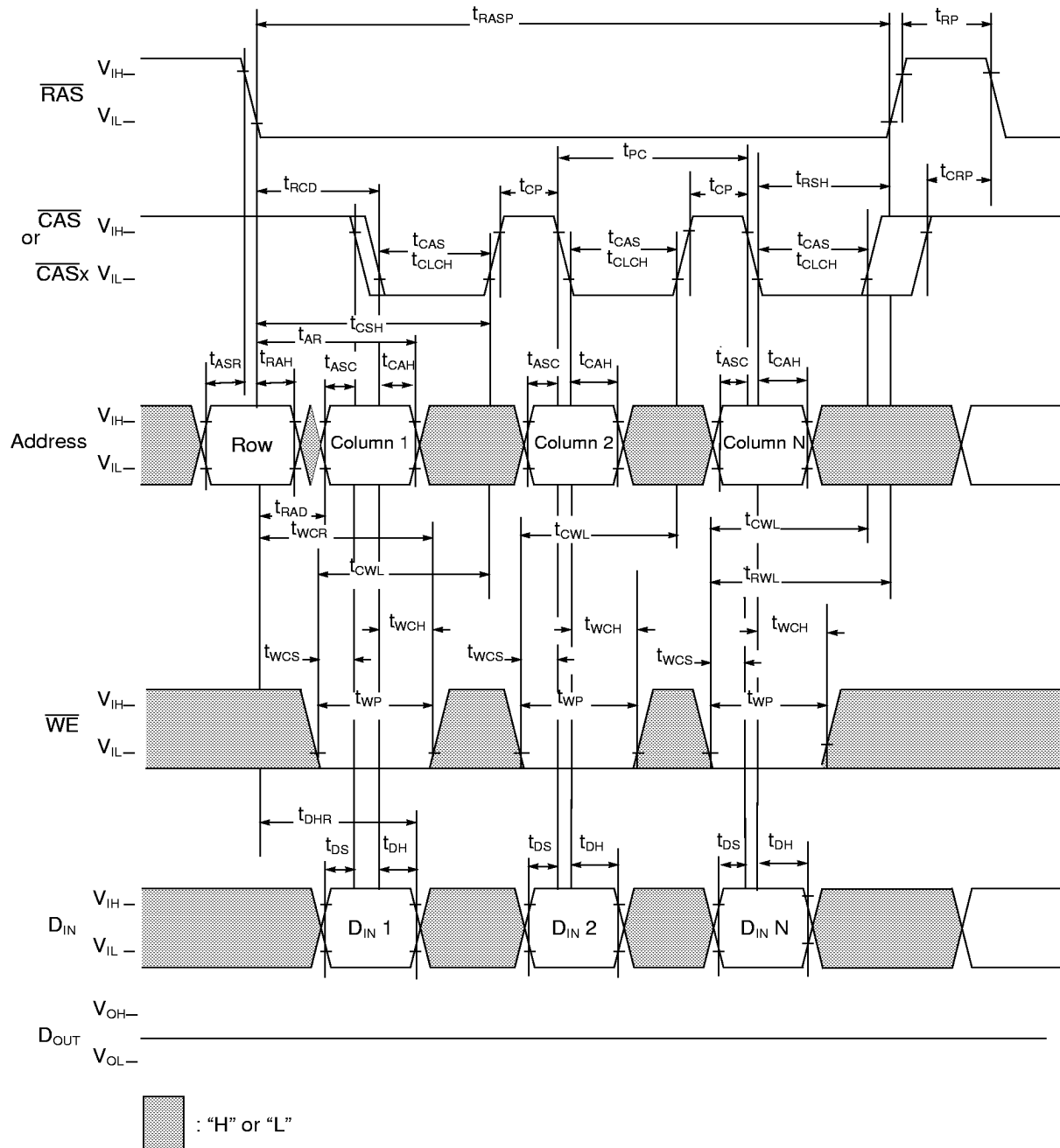


: "H" or "L"

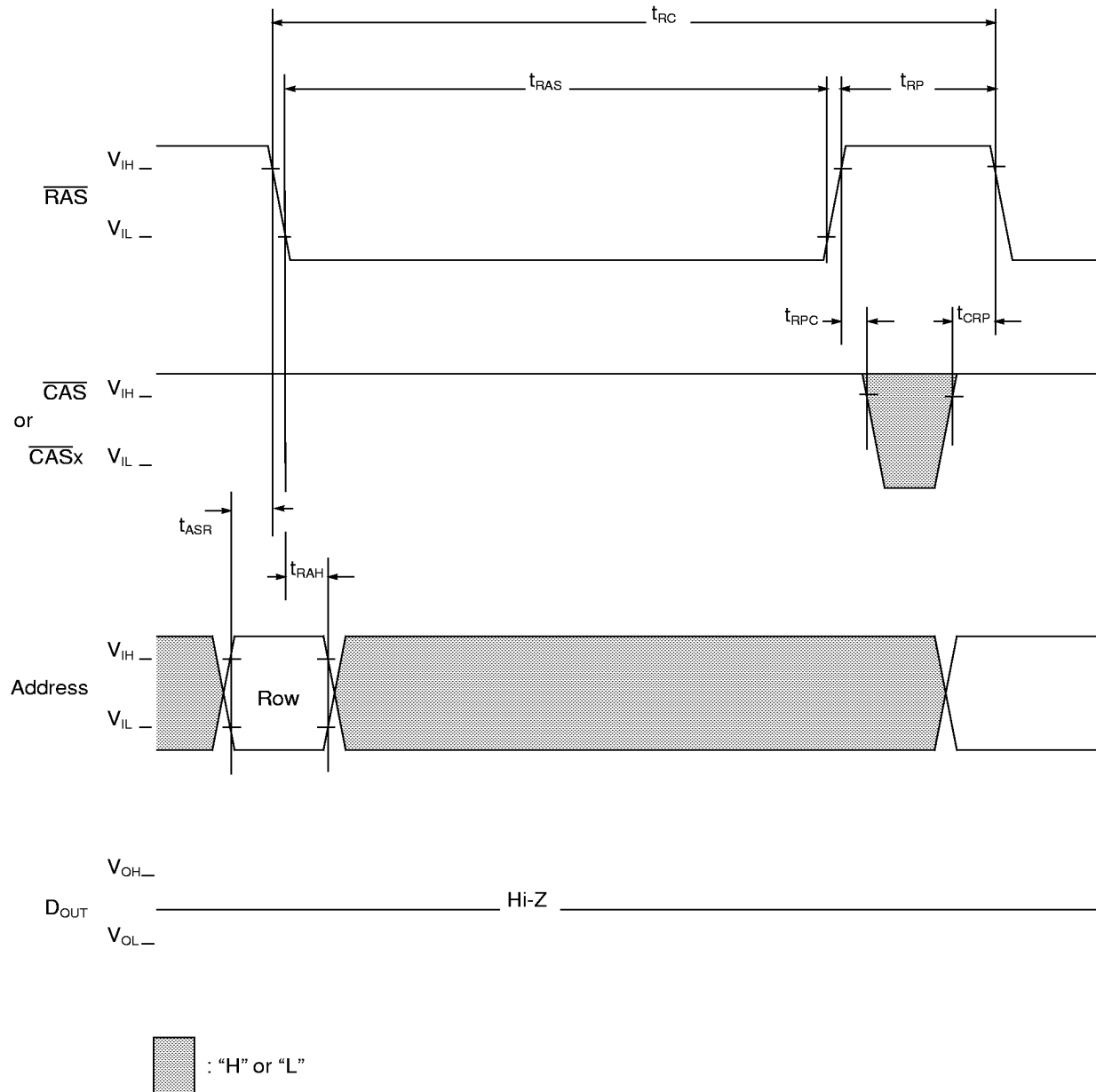
Fast Page Mode Read Cycle



Fast Page Mode Write Cycle

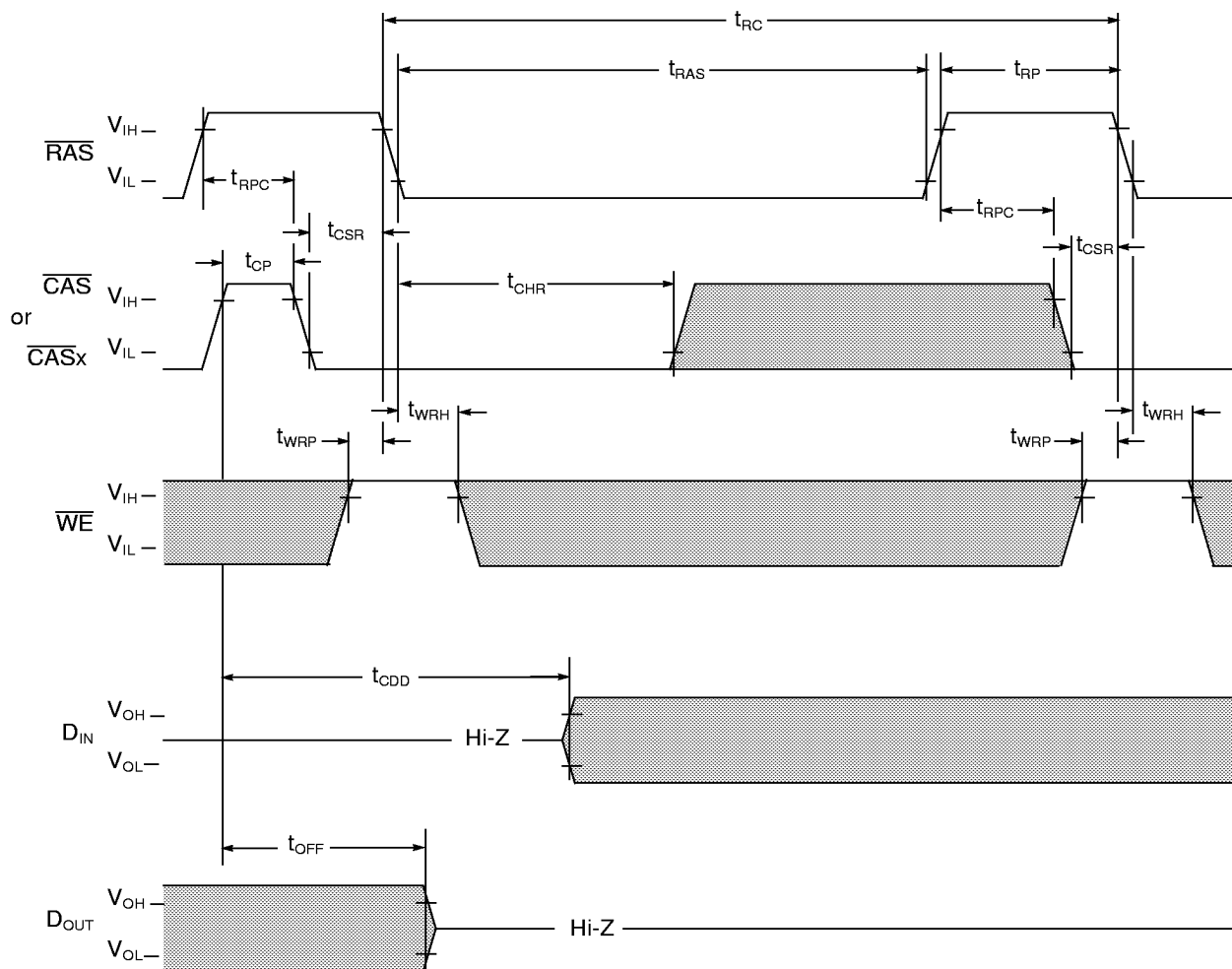


$\overline{\text{RAS}}$ Only Refresh Cycle



Note: $\overline{\text{WE}}$, D_{IN} are "H" or "L"

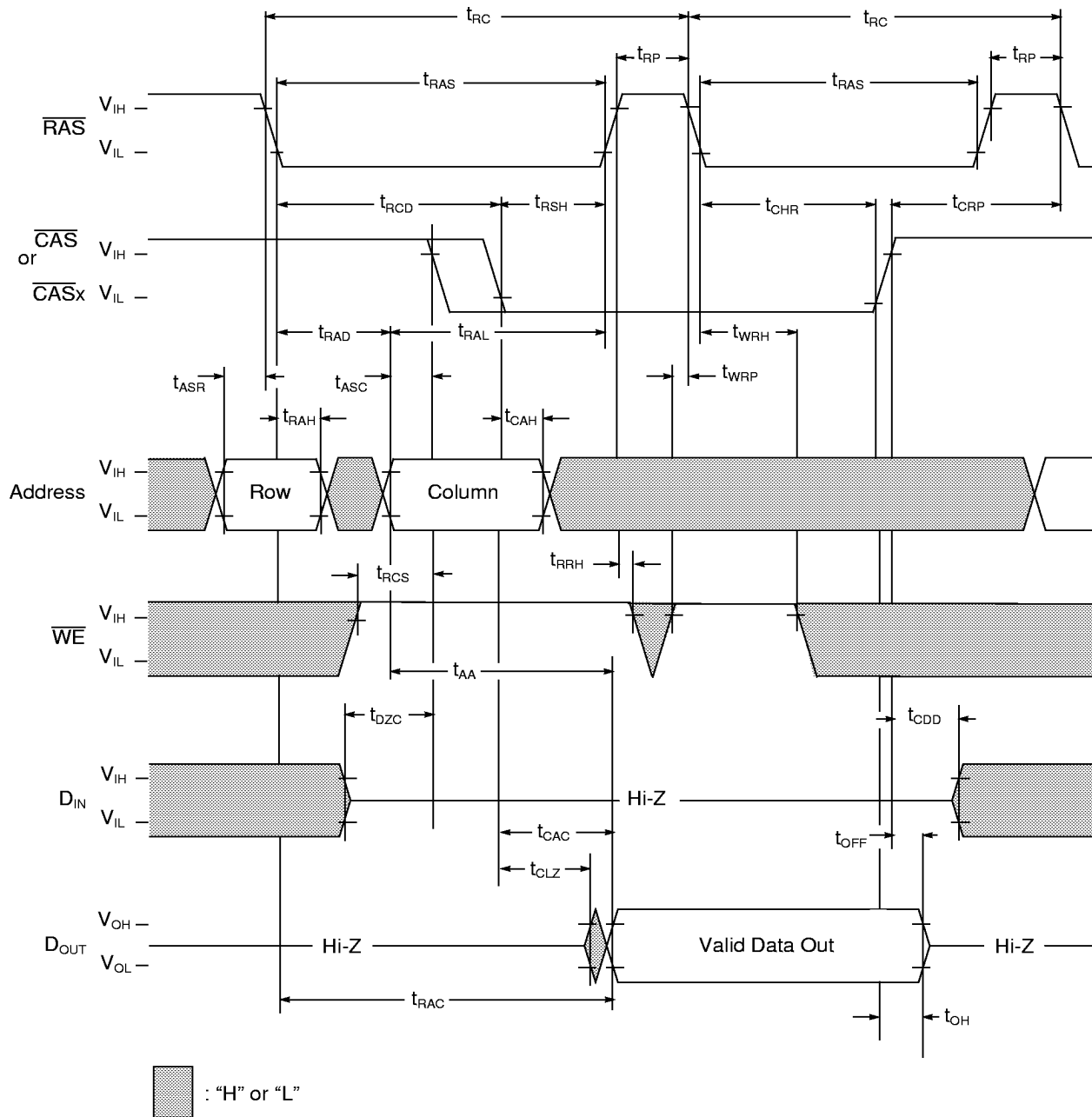
CAS Before RAS Refresh Cycle



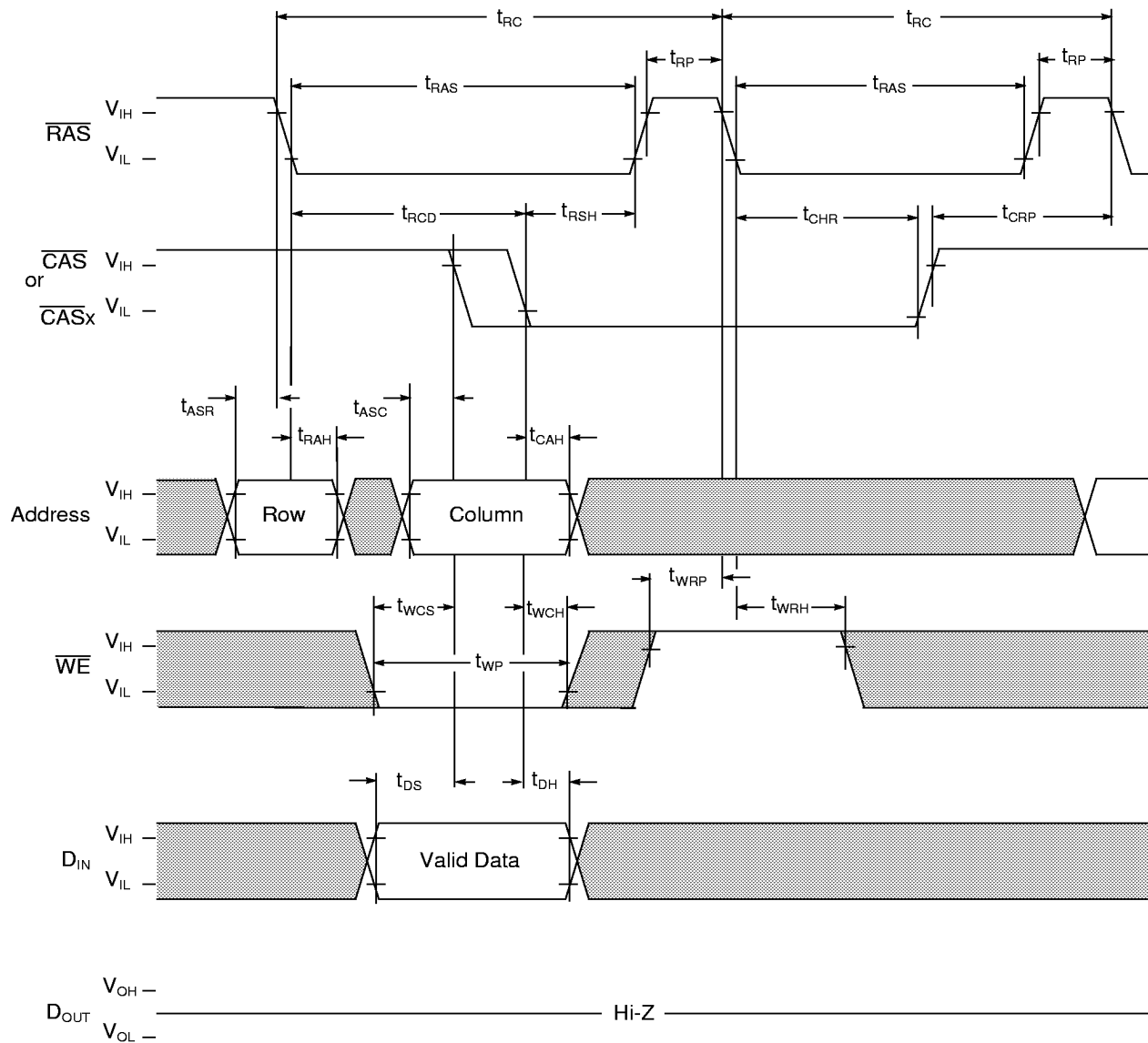
: "H" or "L"

NOTE: Address is "H" or "L"

Hidden Refresh Cycle (Read)

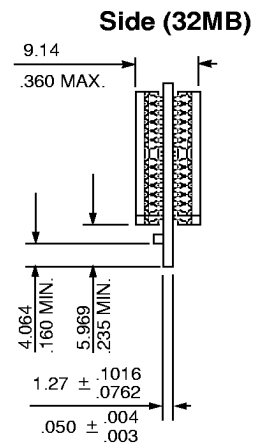
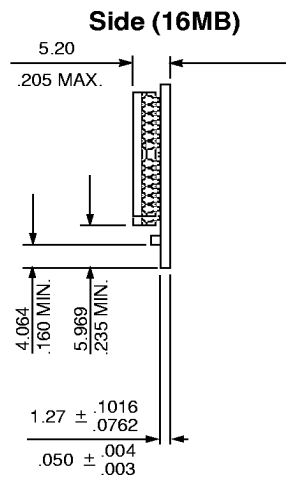
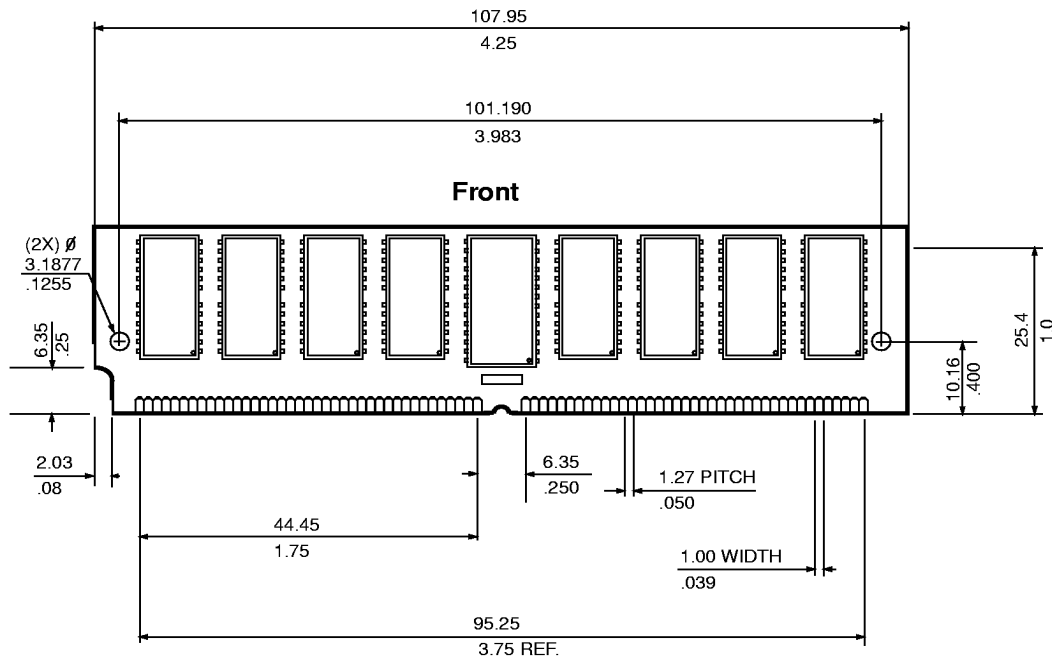


Hidden Refresh Cycle (Write)



: "H" or "L"

Layout Drawing: IBM11D4360E (16MB) & IBM11D8360E (32MB)



Note: All dimensions are typical unless otherwise stated.

Millimeters
Inches



Revision Log

Rev	Contents of Modification
10/96	Initial release of combined datasheet for 4M x 36, 8M x 36